

## 1" Port Plug for 2" Integrating Sphere



Port Plug for Integrating Sphere. Size varies by stock number.

Stock **#89-645** **1 In Stock**

1  MRP ₹35,577

Price inclusive of all taxes

**ADD TO CART**

Volume Pricing	
Qty 1-9	₹35,577 each
Qty 10-24	₹32,019 each
Need More?	<a href="#">Request Quote</a>

### Product Downloads

#### General

2" Sphere, 1.0" Port

**Sphere Compatibility:**

Included with [#58-584](#)

**Note:**

#### Regulatory Compliance

[Compliant](#)

**RoHS 2015:**

Compliant

Reach 209:

[View](#)

Certificate of Conformance:

United States

Country of Origin:

Imported By:

Edmund Optics India Private Limited  
267, Greystone Building, Second Floor,  
6th Cross Rd, Binnamangala,  
Stage 1, Indiranagar, Bengaluru,  
Karnataka, India 560038  
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## Product Details

- Ideal for Measuring Light Sources
- Can be Upgraded to Calibrate Sensors and Test Lenses
- Designed for Simple System Integration

General Purpose Integrating Sphere Systems are designed to spatially integrate radiant flux in order to measure optical radiation. The spheres can be coupled with a sensor to create radiometers, photometers, or spectroradiometers in order to measure the total geometric flux emanating from a light source or the flux density of an illuminated area. Additionally, these sphere systems can be used to measure the output of high power lasers and laser diodes or to measure the reflectance and transmittance of materials.

A variety of accessories are available for modifying or upgrading the performance of the systems, including port plugs, port reducers, and uniform source lamps. Uniform source lamps are ideal for many irradiance applications, such as characterizing the responsivity, linearity, photo response non-uniformity, and dynamic range of focal-plan arrays. Additionally, these sources can be used for evenly illuminating test targets for evaluating the CTF of optical systems or imaging lenses, and for measuring cosine<sup>4</sup> irradiance falloff or other variations in irradiance within optical systems caused by optical aberrations.